

Notice of References Cited	Application/Control No. 10/785,200	Applicant(s)/Patent Under Reexamination HAUVILLE, FRANCOIS P.	
	Examiner Yoon-Young Kim	Art Unit 1723	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2,143,270	01-1939	HUBER MATTHEW W	210/323.1
*	B	US-5,292,432	03-1994	Jainek et al.	210/168
*	C	US-4,159,250	06-1979	Schnell, William J.	210/232
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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